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INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

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Sheet 1 of 1

Complete if Known	
Application Number	Not Yet Assigned
Confirmation Number	Not Yet Assigned
Filing Date	July 29, 2003
First Named Inventor	Ulrich WEGMANN
Art Unit	Not Yet Assigned
Examiner Name	Not Yet Assigned
Attorney Docket Number	Q76579

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
SAT	US 5 965 874			10/12/1999	THE FURUKAWA ELECTRIC CO., LTD
1	US 5 396 329			3/7/1995	BRITISH AEROSPACE PDC
	US 5 298 972			3/29/1994	HEWLETT PACKARD COMPANY
	US 5 227 623			7/13/1993	HEWLETT-PACKARD COMPANY
	US 5 166 752			11/24/1992	RUDOLPH RESEARCH CORPORATION
	US 6 204 924			3/20/2001	EXFO ELECTRO-OPTICAL ENGINEERING INC.
	US 6 312 373	B1		11/6/2001	NIKON CORPORATION
	US 6 344 898	B1		2/5/2002	NIKON CORPORATION
SAT	US 2002/0024673	A1		2/28/2002	CHIDANE OUCHI

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁴
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
SAT	DE	101 09 929	A1		11/22/2001	CARL ZEISS	
1	EP	0 439 127	A2		7/31/1991	HEWLETT-PACKARD COMPANY	
	EP	0 396 409	A2		11/7/1990	THERMA WAVE INC.	
	JP	11-142291	A		5/28/1999	NIKON CORPORATION	Abstract
	WO	02/42728	A1		5/30/2002	NIKON CORPORATION	Abstract
SAT	WO	03/028073	A1		4/3/2003	NIKON CORPORATION	Claims

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
SAT		"OPTICAL SHOP TESTING", EDITED BY DANIEL MALACARA, JOHN WILEY & SONS, INC., SECOND EDITION, PAGES 112-113, 1992, USA.	
SAT		MICHAEL I. SHRIBAK ET AL, "RETURN-PATH POLARIMETER FOR TWO DIMENSIONAL BIREFRINGENCE DISTRIBUTION MEASUREMENT", JULY 1999, SPIE, PAGES 144-145 AND 148-149, VOLUME 3654, DENVER COLORADO	
SAT		S. BEREZHNA, ET AL, "ACCURACY OF WHOLE-FIELD MAPPING BY JONES MATRIX FOURIER PHOTOPOLARIMETER", 2000, PROCEEDINGS OF SPIE, PAGES 81-89, VOLUME 4148	

Examiner Signature	S. A. Truca	Date Considered	2-13-06
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to indicate here if English language Translation is attached.